

Notice of References Cited

Application/Control No.

10/595,686

Applicant(s)/Patent Under

Reexamination

CHOY ET AL.

Examiner

REBECCA LEE

Art Unit

1793

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
B	US-			
C	US-			
D	US-			
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FOREIGN PATENT DOCUMENTS

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N					
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T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Greene et al. "low-Temperature Wafer-Scale production of ZnO nanowire Arrays", Angew. Chem. Int. Ed. 2003, 42, 3031-3034
V	
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X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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